2020년 2월 14일(금), 09:00~10:30

Room H (하트 I, 6층)

Q. Metrology, Inspection, and Yield Enhancement 분과

[FH1-Q] Nanoanalysis and Characterization

FH1-Q-1 **09:00~09:30**	**[초청]** **Spectroscopic Ellipsometric Study on Temperature Dependence Dielectric Functions and Critical Point Energies for 2D Materials** Tae Jung Kim[1], Hoang Tung Nguyen[1], Van Long Le[1], Xuan Au Nguyen[1], Do Hyoung Koo[2], Chul-Ho Lee[2], Farman Ullah[3], Yong Soo Kim[3], and Young Dong Kim[1] *[1]Department of Physics, Kyung Hee University, [2]KU-KIST Graduate School of Converging Science & Technology, Korea University, [3]Department of Physics and Energy Harvest Storage Research Center (EHSRC), University of Ulsan*
FH1-Q-2 **09:30~10:00**	**[초청]** **Redefinition of kg Using Kibble Balance and its Application in Semiconductor Metrology** Dongmin Kim *KRISS*
FH1-Q-3 **10:00~10:30**	**[초청]Confocal Thermo-Reflectance Microscope and Applications** Ki Soo Chang[1], Dong Uk Kim[1], Chan Bae Jeong[1], Ilkyu Han[1], Jung Dae Kim[1], Hyun Hwangbo[1], Seung-Woo Lee[2], and Byung-Seon Chun[2] *[1]Division of Scientific Instrumentation, KBSI, [2]Nanoscope Systems, Inc.*